	Type	Hits	Search Text	DBs	Time Stamp
1	BRS	2	"6358800".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/12 19:06
2	BRS	12	("5434093" "5448094" "5668021" "5780340" "6033980" "6087208" "6100146" "6117712" "6130454" "6171916" "6204128" "6204133").PN.	USPAT	2004/09/12 19:06
3	BRS	1	"6358,800".URPN.	USPAT	2004/09/12 19:08
4	BRS	9936	transistor with (recess trench)	IH: D() • . I D() •	2004/09/12 19:47
5	BRS	1320	transistor with (recess trench) and etching with isolation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/12 19:42
6	BRS	294		IN D() I D() .	2004/09/12 19:47
7	BRS	11293	(gate transistor) near3 (recess trench)	IN. DI 1 * . I DI 1 *	2004/09/12 19:47
8	BRS	622	(recess trench)) and etching near3 ((trench adj isolation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/12 19:49
9	BRS	42	near3 ((trench adj isolation) or (STI) or isolation or (field adj oxide)) same active	EPO; JPO;	2005/03/09 18:57

	Туре	Hits	Search Text	DBs	Time Stamp
10	BRS	758	257/328.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 19:20
11	BRS	611	257/329.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 19:20
12	BRS	984	257/330.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 19:20
13	BRS	342	257/332.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 19:20
14	BRS	188	257/334.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/15 19:20
15	BRS	781	257/336.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 19:20
16	BRS	239	257/337.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/09/15 19:20
17	BRS	1097	((gate transistor) near3 (recess trench)) and low\$3 near2 (source drain)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/03/09 18:56

	Туре	Hits	Search Text	DBs	Time Stamp
18	BRS	7	near3 ((trench adj isolation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/03/09 18:59
19	BRS	124	((gate transistor) near3 (recess trench)) and ((trench adj isolation) or (STI) or isolation or (field adj oxide)) same active adj region and low\$3 near2 (source drain)	EPO; JPO;	2005/03/09 19:00
20	BRS	83	((gate transistor) near3 (recess trench)) and ((trench adj isolation) or (STI) or isolation or (field adj oxide)) same active adj region and low\$3 near2 (source drain) and junction	USPAT; EPO; JPO; DERWENT;	2005/03/09 19:00
21	BRS	38	((gate transistor) near3 (recess trench)) and ((trench adj isolation) or (STI) or isolation or (field adj oxide)) same active adj region and low\$3 near2 (source drain) and junction and spacer	USPAT; EPO; JPO; DERWENT;	2005/03/09 19:01
22	BRS	45	((gate transistor) near3 (recess trench)) and ((trench adj isolation) or (STI) or isolation or (field adj oxide)) same active adj region and low\$3 near2 (source drain) and spacer	USPAT; EPO; JPO; DERWENT;	2005/03/09 19:01
23	BRS	725081	((gate transistor) near3 (recess trench)) and ((trench adj isolation) or (STI) or isolation or (field adj oxide)) same active adj region and low\$3 near2 (source drain) and spacer iwth (trench recess)	IN' D() • . I D() •	2005/03/09 19:01

	Туре	Hits	Search Text	DBs	Time Stamp
24	BRS	19	isolation or (STI) or isolation or (field adjoxide) same active adj region	16'D(10 .1D(10	2005/03/09 19:01
25	BRS	14	isolation or (STI) or isolation or (field adjoxide)) same active adj region and lows near (source drain)	H: D() • . D() •	2005/03/09 19:01